# Application/Control No. 09/729,162 Applicant(s)/Patent Under Reexamination HOSHINO ET AL. Examiner Dennis M. Butler Art Unit Page 1 of 1

# **Notice of References Cited**

### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-2002/0014537	02-2002	Obana et al.	235/492
	В	US-6,536,671	03-2003	Baentsch, Michael	235/487 .
	С	US-6,233,169	05-2001	Nishimura, Kiyoshi	365/145
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				1	
	0					
	Р					
	Q					
	R				, ,	
	S		,			
	Т					

### **NON-PATENT DOCUMENTS**

	NOT FAILURE DOGINERIO								
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)							
	U								
	V								
	w								
	x								

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.